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## VERIFICATION OF EMC COMPLIANCE

Verification No.: GLEMR070200302ITEV  
Applicant: ISS MANUFACTURING LTD.  
Address of Applicant: UNIT 604-606, 6/F., PHASE II, CHAI WAN  
INDUSTRIAL CITY, 70 WING TAI ROAD, CHAI WAN,  
HONGKONG  
Product Description: USB PHONE  
Model No: STX-5013 / STY-5015  
Sufficient samples of the product have been tested and found to be in conformity with  
EN 55022 : 1998+A1:2000+A2:2003  
EN 55024 :1998+A1: 2001+A2:2003  
Test Standard: EN 61000-3-2:2000 +A2:2005  
EN 61000-3-3 : 1995 + A1: 2001  
As shown in the  
Test Report Number(s): GLEMR070200302ITE

This verification of EMC Compliance has been granted to the applicant based on the results of the tests, performed by laboratory of SGS-CSTC Standards Technical Services Co., Ltd. on the sample of the above-mentioned product in accordance with the provisions of the relevant specific standards and Directive 2004/108/EC as last amended by Directive 93/68/EEC. The CE mark as shown below can be used, under the responsibility of the manufacturer, after completion of an EC Declaration of Conformity and compliance with all relevant EC Directives. The affixing of the CE marking presumes in addition that the conditions in annexes III and V of the Directive are fulfilled.



Date: 14 March 2007

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Member of the SGS Group (SGS SA)

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Report No.: GLEMR070200302ITE  
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### TEST REPORT

**Application No.:** GLEMR070200302IT  
**Applicant:** ISS MANUFACTURING LTD.  
**Equipment Under Test (EUT):**  
**EUT Name:** USB PHONE  
**Item No.:** STX-5013 / STY-5015\*  
**Serial No.:** Not supplied by client

\* Please refer to section 2 of this report which indicates which item was actually tested and which were electrically identical.

**Standards:** EN 55022 : 1998+A1:2000+A2:2003  
EN 55024 :1998+A1: 2001+A2:2003  
EN 61000-3-2:2000 +A2:2005  
EN 61000-3-3 : 1995 + A1: 2001

**Date of Receipt:** 05 February 2007  
**Date of Test:** 08 February to 12 March 2007  
**Date of Issue:** 14 March 2007

<b>Test Result :</b>	<b>PASS*</b>
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\* In the configuration tested, the EUT complied with the standards specified above.

The CE mark as shown below can be used, under the responsibility of the manufacturer, after completion of an EC Declaration of Conformity and compliance with all relevant EC Directives.



This report refers to the General Conditions for Inspection and Testing Services, printed overleaf.  
This report details the results of the testing carried out on one sample. The results contained in this test report do not relate to other samples of the same product and does not permit the use of the SGS PRODUCT CERTIFICATION MARK. The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report.  
This report may only be reproduced and distributed in full. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards. Any mention of SGS International Electrical Approvals or testing done by SGS International Electrical Approvals in connection with, distribution or use of the product described in this report must be approved by SGS International Electrical Approvals in writing.  
The report must not be used by the client to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the federal government.  
All test results in this report can be traceable to National or International Standards.

## 2 Test Summary

The EUT has been tested with a USB PHONE.				
Test	Test Requirement	Test Method	Class / Severity	Result
Radiated Emission, 30MHz to 1GHz	EN 55022 :1998 + A1:2000+A2:2003	EN 55022 :1998 + A1:2000+A2:2003	Class B	PASS
Conducted Emission (150KHz to 30MHz)	EN 55022 :1998 + A1:2000+A2:2003	EN 55022 :1998 + A1:2000+A2:2003	Class B	PASS
Harmonic Emission on AC, 50Hz	EN 61000-3-2:2000 +A2:2005	EN 61000-3-2:2000 +A2:2005	N/A	N/A
Flicker Emission on AC	EN 61000-3-3 :1995 + A1:2001	EN 61000-3-3 :1995 + A1:2001	N/A	N/A
ESD	EN 55024 :1998 + A1:2001+A2:2003	EN 61000-4-2 :1995 + A1:1998+A2:2001	Contact ±4 kV Air ±8 kV	PASS①
Radiated Immunity, 80MHz to 1 GHz	EN 55024 :1998 + A1:2001+A2:2003	EN 61000-4-3 :2002 + A1:2002	3V/m 80%, 1kHz, AM	PASS
Electrical Fast Transients (EFT) on AC	EN 55024 :1998 + A1:2001+A2:2003	EN 61000-4-4 :1995 + A1:2001+A2:2001	AC ± 1.0kV	PASS ②
Surge Immunity on AC	EN 55024 :1998 + A1:2001+A2:2003	EN 61000-4-5 :1995 + A1:2001	±1kV D.M. † ±2kV C.M. ‡	PASS
Injected Currents on AC, 150kHz to 80MHz	EN 55024 :1998 + A1:2001+A2:2003	EN 61000-4-6 :1996 + A1:2001	3Vrms (emf), 80%, 1kHz Amp. Mod.	PASS
Voltage Dips and Interruptions on AC	EN 55024 :1998 + A1: 2001+A2:2003	EN 61000-4-11 :1994 + A1:2001	0 % $U_T^*$ for 0.5per 0 % $U_T^*$ for 250per 70 % $U_T^*$ for 25per	PASS

\*  $U_T$  is the nominal supply voltage

† D.M. – Differential Mode

‡ C.M. – Common Mode

N/A: not applicable. Please refer to Section 6.3 & Section 6.4 for further details.

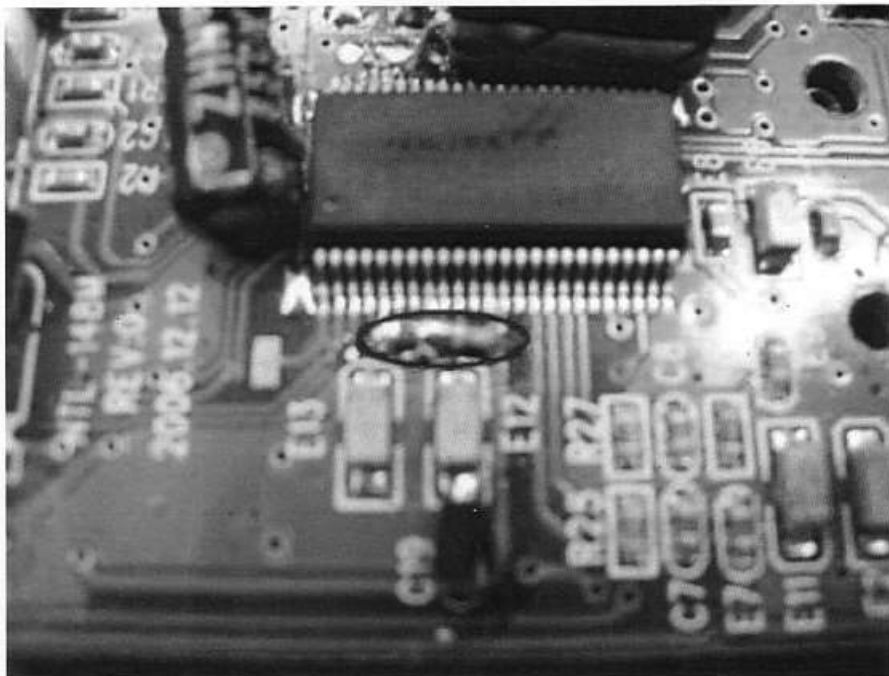
Remark:

♣:Item number: STX-5013 / STY-5015

According to the confirmation from the applicant, all models were electrical circuit design, layout, components used and internal wiring were identical for the above items, only difference being the model STX-5015 with LCD, but model STX-5013 without LCD. Therefore only one item STY-5015 was tested in this report.

①-②: The EUT passed the ESD and EFT tests after modifications as shown as below:

1. Replace the Capacitor C12 with an Electrolytic capacitor which is 4.7 $\mu$ F/10V.
2. Add two Capacitors parallel connected with E13 and C19 as the photos shown:



3. Replace the Capacitor E3 and E5 with new ones which are 100 $\mu$ F/10V.

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## 4 General Information

### 4.1 Client Information

Applicant: ISS MANUFACTURING LTD.  
 Address of Applicant: UNIT 604-606, 6/F., PHASE II, CHAI WAN INDUSTRIAL CITY, 70 WING TAI ROAD, CHAI WAN, HONGKONG

### 4.2 General Description of E.U.T.

EUT Name: USB PHONE  
 Item No.: STX-5013 / STY-5015  
 Serial No.: Not supplied by client

### 4.3 Details of E.U.T.

Power Supply: Supply by PC USB port  
 Power Cord: 2m unscreened with ferrite USB cable

### 4.4 Description of Support Units

The EUT has been tested with PC system.

Description	Manufacturer	Model No.	Common
Personal Computer	IBM	P7314A	EMC0035
15" Monitor	DELL	E551C	LO206HIOIA1
Mouse	IBM	MU29J	
Keyboard	IBM	SK-8820	
ROM Programmer	DASI Electronics	EMP-100A	
Printer	Hewlett-Packard	C5884A	DeskJet 670C
NoteBook	IBM	T40	EMC0034
NoteBook	IBM	X22	Just for CE test only

### 4.5 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services Co., Ltd., Guangzhou EMC Laboratory, No.198 Kezhu Road, Science Town Economic & Technology Development District Guangzhou, China 510663

Tel: +86 20 82155555

Fax: +86 20 82075059

No tests were sub-contracted.

#### 4.6 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

- **NVLAP – Lab Code: 200611-0**

SGS-CSTC Standards Technical Services Co., Ltd., Guangzhou EMC Laboratory is recognized under the National Voluntary Laboratory Accreditation Program (NVLAP/NIST). NVLAP Code: 200611-0.

- **ACA**

SGS-CSTC Standards Technical Services Co., Ltd., EMC Laboratory can also perform testing for the Australian C-Tick mark as a result of our NVLAP accreditation.

- **SGS UK(Certificate No.: 32), SGS-TUV SAARLAND and SGS-FIMKO**

Have approved SGS-CSTC Standards Technical Services Co., Ltd., EMC Laboratory as a supplier of EMC TESTING SERVICES and SAFETY TESTING SERVICES.

- **CNAS L0167**

SGS-CSTC Standards Technical Services Co., Ltd., EMC Laboratory has been assessed and in compliance with CNAS-CL01:2006 accreditation criteria for testing laboratories (identical to ISO/IEC 17025:2005 General Requirements) for the Competence of Testing Laboratories.

- **FCC – Registration No.: 282399**

SGS-CSTC Standards Technical Services Co., Ltd., EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files. Registration 282399, May 31, 2002. With the above and NVLAP's accreditation, SGS-CSTC is an authorized test laboratory for the DoC process.

- **Industry Canada (IC)**

The 3m/10m Alternate Semi-anechoic chamber of SGS-CSTC Standards Technical Services Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 4620B-1.

Date of Registration: Jan 15, 2007. Valid until Jan 15, 2009

- **VCCI**

The 10m Semi-anechoic chamber and Shielded Room of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: R-2460 and C-2584 respectively.

This certificate is valid until September 14, 2009

#### 4.7 Deviation from Standards

None.

#### 4.8 Abnormalities from Standard Conditions

The EUT passed the ESD and EFT tests after modifications.

#### 4.9 Monitoring of EUT for All Immunity Test

Visual: Monitored the LCD of the EUT and the display of PC monitor.

Audio: Monitored the sound of the EUT.

## 5 Equipments Used during Test

RE in Chamber/OATS						
No:	Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date (dd-mm-yy)	Cal. Due date (dd-mm-yy)
EMC0525	Compact Semi-Anechoic Chamber	ChangZhou ZhongYu	N/A	N/A	06-03-2006	06-03-2007
EMC0522	EMI Test Receiver	Rohde & Schwarz	ESIB26	100249	05-12-2006	05-12-2007
N/A	EMI Test Software	Audix	E3	N/A	N/A	N/A
EMC0514	Coaxial cable	SGS	N/A	N/A	04-12-2006	04-12-2007
EMC0524	Bi-log Type Antenna	Schaffner -Chase	CBL6112B	2966	31-10-2006	31-10-2007
EMC0519	Bilog Type Antenna	Schaffner -Chase	CBL6143	5070	31-07-2006	31-07-2007
EMC0517	Horn Antenna	Rohde & Schwarz	HF906	100095	29-07-2006	29-07-2007
EMC0040	Spectrum Analyzer	Rohde & Schwarz	FSP30	100324	05-12-2006	05-12-2007
EMC0520	0.1-1300 MHz Pre-Amplifier	HP	8447D OPT 010	2944A06252	06-03-2006	06-03-2007
EMC0521	1-26.5 GHz Pre-Amplifier	Agilent	8449B	3008A01649	06-03-2006	06-03-2007
EMC0523	Active Loop Antenna	EMCO	6502	00042963	09-08-2006	09-08-2008
EMC0530	10m Semi-Anechoic Chamber	ETS	N/A	N/A	22-08-2006	22-08-2007

Conducted Emission						
No:	Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date (dd-mm-yy)	Cal. Due date (dd-mm-yy)
EMC0306	Shielding Room	Zhong Yu	8 x 3 x 3.8 m <sup>3</sup>	N/A	N/A	N/A
EMC0102	LISN	Schaffner Chase	MNZ050D/1	1421	05-12-2006	05-12-2007
EMC0506	EMI Test Receiver	Rohde & Schwarz	ESCS30	100085	05-12-2006	05-12-2007
EMC0107	Coaxial Cable	SGS	2m	N/A	25-11-2006	25-11-2007

ESD						
No:	Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date (dd-mm-yy)	Cal. Due date (dd-mm-yy)
SEL0012	ESD Gun	Keytek	MZ-15/EC	0502182	20-12-2006	20-12-2007
EMC0804	ESD Ground Plane	SGS	3m x 3m	N/A	N/A	N/A

EFT, Surge, Voltage dips and Interruption						
No:	Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date (dd-mm-yy)	Cal. Due date (dd-mm-yy)
EMC1010	EMC Immunity Test System	Thermo KeyTek	Pro-Plus	0501276	05-12-2006	05-12-2007
EMC1009	Capacitive Coupling Clamp	Thermo KeyTek	Pro-CCL	0501362	05-12-2006	05-12-2007
EMC1005	Digital Oscilloscope	Tektronix	TDS3012	B015508	14-07-2006	14-07-2007

Radiated Immunity						
No:	Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date (dd-mm-yy)	Cal. Due date (dd-mm-yy)
EMC0525	Compact 3m Semi- Anechoic Chamber	Changzhou zhongyu	N/A	N/A	06-03-2006	06-03-2007
EMC0516	Signal Generator	Rohde & Schwarz	SMR20	100416	05-12-2006	05-12-2007
EMC0915	Amplifier 20M-1GHz	EMPOWER	BBS2E4ALP	1007	06-03-2006	06-03-2007
EMC0914	Amplifier 800M-2.5GHz	EMPOWER	BBS3Q5KIN	1006	06-03-2006	06-03-2007
EMC0904	Power Meter	Rohde & Schwarz	NRVS	825770/074	22-07-2006	22-07-2007
EMC0905	Power Sensor	Rohde & Schwarz	NRV-Z5	825802/013	22-07-2006	22-07-2007
EMC0917	Dual Directional Coupler	EMCA	715-10-1.400	070031	06-10-2005	06-10-2007
EMC0907	Electric Field Probe	Wandel & Goltermann	EMC-20	M-0063	26-04-2006	25-04-2007
EMC0908	Oscilloscope Type 485	Tektronix	485	B144408	21-07-2006	21-07-2007
EMC0909	Monitor System	Mitsubish Corp.	M-0552AB	91510185	N/A	N/A
EMC0524	Bi-log Type Antenna	Schaffner -Chase	CBL6112B	2966	31-10-2006	31-10-2007
EMC0916	Microwave Horn Antenna(0.8-5GHz)	Amplifier Research	AT4002A	308071	25-10-2006	25-10-2007

Conducted Immunity						
No:	Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date (dd-mm-yy)	Cal. Due date (dd-mm-yy)
EMC1101	Signal Generator	Rohde & Schwarz	SMY01	825675/016	19-09-2006	18-09-2007
EMC1102	Amplifier 0.15-230MHz	Ophirrf	GRF5048	1003	06-03-2006	06-03-2007
EMC1103	Power Meter	Rohde & Schwarz	NRVS	825770/079	22-07-2006	22-07-2007
EMC0905	Power Sensor	Rohde & Schwarz	NRV-Z5	825802/013	22-07-2006	22-07-2007
EMC1105	Dual Directional coupler	Werlatone Inc.	C1795	6635	24-11-2006	24-11-2007
EMC0908	Oscilloscope Type 485	Tektronix	485	B144408	21-07-2006	21-07-2007
EMC1108	CDN M3	Schaffner Chase	CDN-M3-16	9866	05-12-2006	05-12-2007
EMC1107	CDN M2	Schaffner Chase	CDN-M2-16	9863	05-12-2006	05-12-2007
EMC1120	Immunity SW Ver 4.31	Schaffner Chase	CIS9942	WHHPKB	N/A	N/A
EMC1116	Current Probe	Schaffner Chase	CIP9136	1155	25-11-2006	25-11-2007
EMC1117	Current Probe	Schaffner Chase	CSP8445	18	25-11-2006	25-11-2007

General used equipment						
No:	Test Equipment	Manufacturer	Model No.	Serial No.	Cal. Date (dd-mm-yy)	Cal. Due date (dd-mm-yy)
EMC0050-EMC0053	Temperature, & Humidity	ZHENGZHOU BO YANG	WSB	N/A	05-12-2006	05-12-2007
EMC0054	Temperature, & Humidity	Shenzhen Tai Kong	THG-1	N/A	04-01-2007	04-01-2008
EMC0006	DMM	Fluke	73	70681569	27-09-2006	27-09-2007
EMC0007	DMM	Fluke	73	70671122	27-09-2006	27-09-2007

## 6 Emission Test Results

### 6.1 Radiated Emissions, 30MHz to 1GHz

Test Requirement:	EN 55022
Test Method:	EN 55022
Test Date:	08 February 2007
Frequency Range:	30MHz to 1GHz
Measurement Distance:	3m
Class:	Class B
Detector:	Peak for pre-scan Quasi-Peak if maximised peak within 6dB of limit

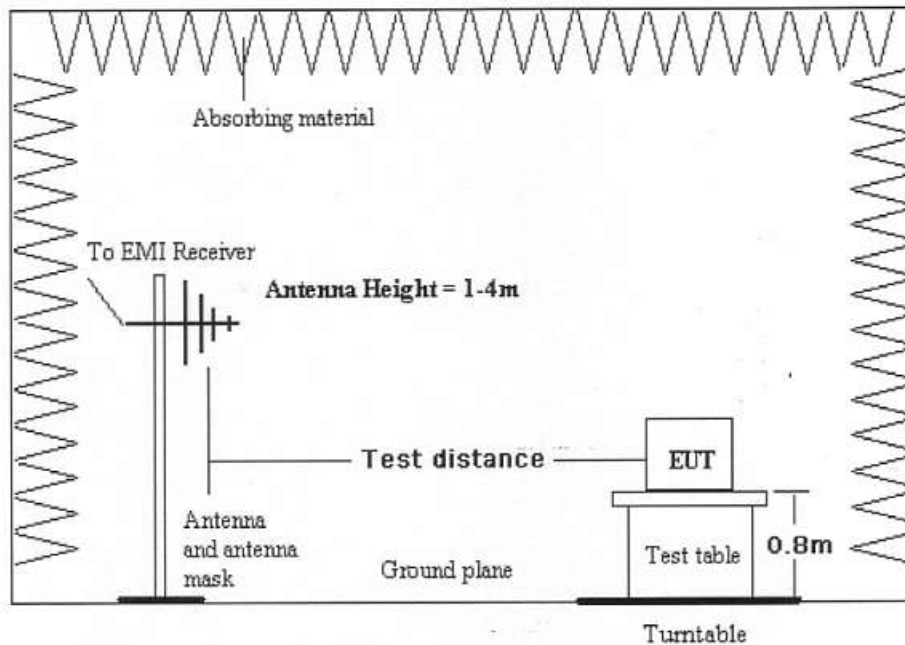
#### 6.1.1 E.U.T. Operation

Operating Environment:

Temperature: 25 °C Humidity: 47% RH Atmospheric Pressure: 1008 mbar

EUT Operation: Test the EUT in communication mode, running the software supplied by application.

#### 6.1.2 Test Setup



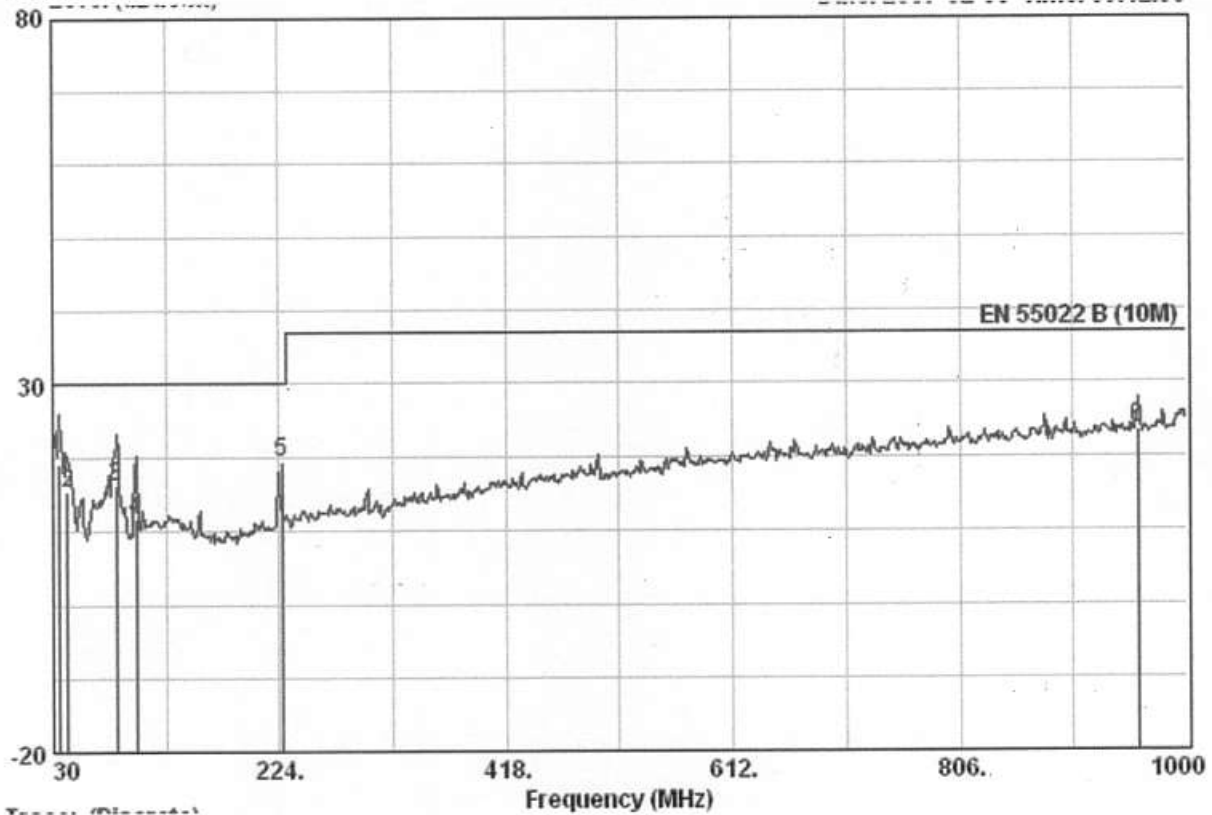
#### 6.1.3 Measurement Data

An initial pre-scan was performed in the 10m chamber using the spectrum analyser in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bilog antenna with 2 orthogonal polarities.

The following quasi-peak measurements were performed on the EUT on 08 February 2007:

Vertical:

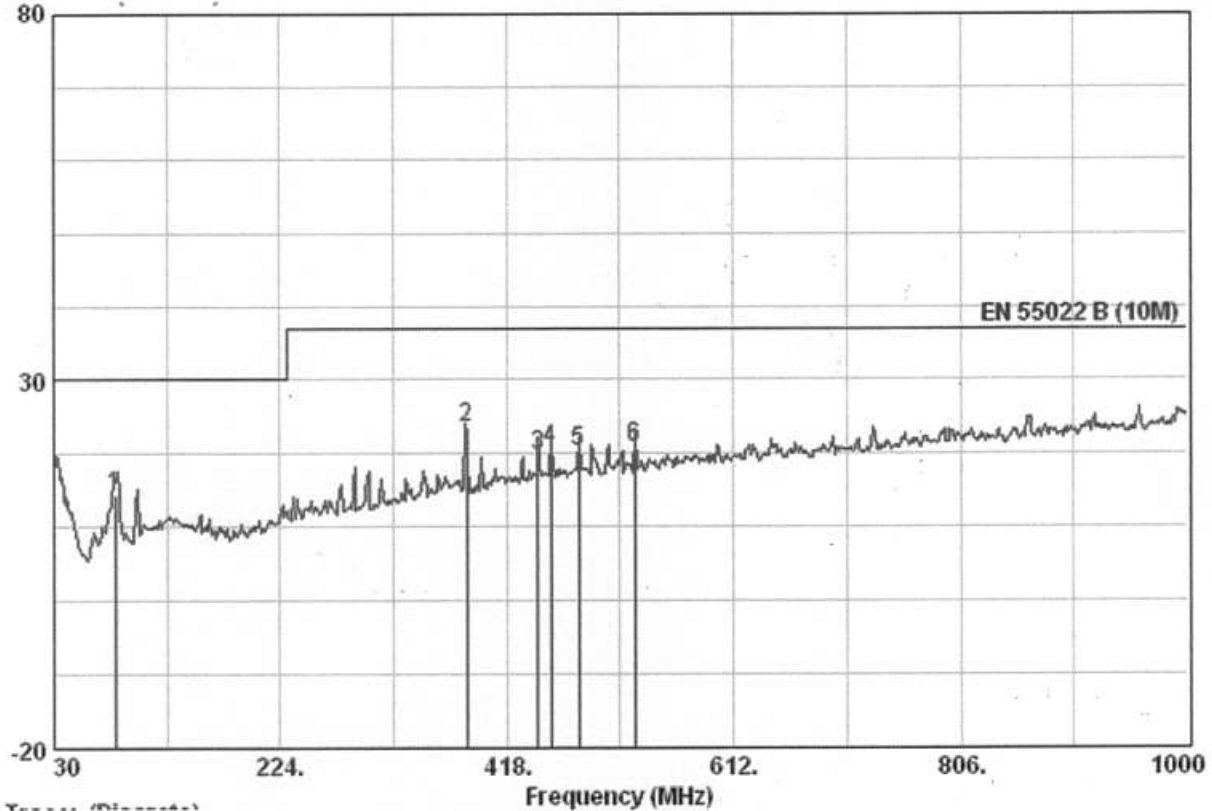
Peak scan



Quasi-peak measurement

	Freq	Level	Limit	Read	Antenna	Cable	Preamp	Over	
	MHz	dBuV/m	Line	Level	Factor	Loss	Factor	Limit	Remark
			dBuV/m	dBuV	dB/m	dB	dB	dB	
1	34.850	19.19	30.00	28.39	18.10	0.90	28.20	-10.81	QP
2	42.610	15.45	30.00	29.50	13.20	0.90	28.15	-14.55	QP
3	84.320	16.12	30.00	30.77	11.95	1.40	28.00	-13.88	QP
4	101.780	11.70	30.00	30.10	8.00	1.50	27.90	-18.30	QP
5	225.940	19.52	30.00	34.35	10.40	2.10	27.34	-10.48	QP
6	958.290	23.47	37.00	26.35	20.10	4.70	27.69	-13.53	QP

Horizontal:  
 Peak scan



Quasi-peak measurement

	Freq	Level	Limit	ReadAntenna	Cable	Preamp	Over	
	MHz	dBuV/m	Line	Level	Factor	Loss	Factor	Limit Remark
			dBuV/m	dBuV	dB/m	dB	dB	dB
1	82.380	14.25	30.00	29.00	11.95	1.30	28.00	-15.75 QP
2	384.120	23.47	37.00	34.64	13.77	2.90	27.84	-13.53 QP
3	444.190	19.87	37.00	29.77	15.10	3.20	28.20	-17.13 QP
4	455.830	20.69	37.00	30.39	15.35	3.20	28.25	-16.31 QP
5	479.110	20.20	37.00	29.46	15.74	3.30	28.30	-16.80 QP
6	527.610	20.85	37.00	29.62	16.23	3.40	28.40	-16.15 QP

1. Level = Read Level + Antenna Factor + Cable Loss – Preamp Factor.

2. 0° was the table front facing the antenna. Degree is calculated from 0° clockwise facing the antenna.

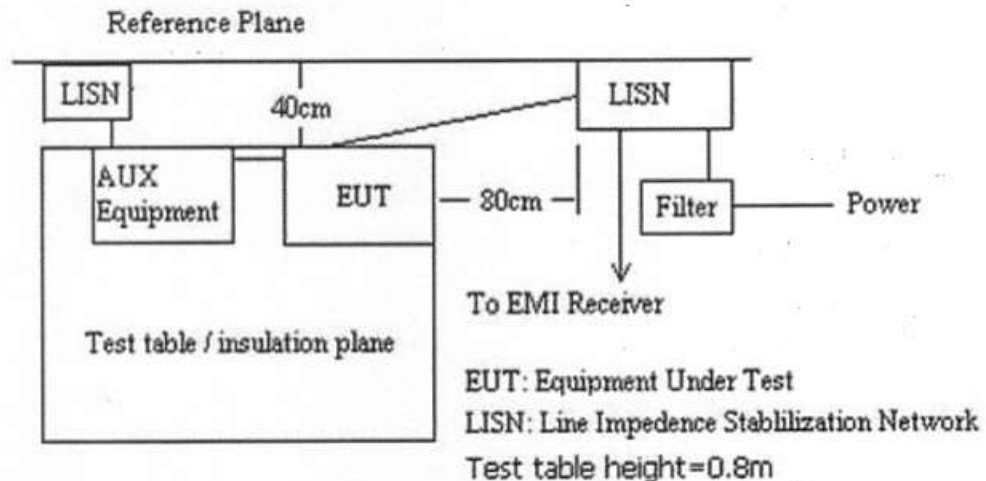
## 6.2 Conducted Emissions Mains Terminals, 150kHz to 30MHz

Test Requirement: EN 55022  
 Test Method: EN 55022  
 Test Date: 08 February 2007  
 Frequency Range: 150KHz to 30MHz  
 Class / Severity: Class B  
 Detector: Peak for pre-scan (9kHz Resolution Bandwidth)  
 Quasi-Peak if maximised peak within 6dB of Quasi-Peak limit

### 6.2.1 E.U.T. Operation

Operating Environment:  
 Temperature: 21 °C Humidity: 52 % RH Atmospheric Pressure: 1011 mbar  
 EUT Operation: Test the EUT in communication mode, running the software supply by application.

### 6.2.2 Plan View of Test Setup



### 6.2.3 Measurement Data

An initial pre-scan was performed on the live and neutral lines with peak detector.

Quasi-Peak and Average measurement were performed at the frequencies with maximized peak emission were detected.

The following Quasi-Peak and Average measurements were performed on the EUT on 08 February 2007: